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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

*(Use as many sheets as necessary)*

Sheet

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of

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Application Number

10/620,628

Filing Date

7/15/2003

First Named Inventor:

John X. Zhong

Examiner: Stacy Whitmore

GROUP: 2812 2825Attorney Docket Number **SYN-0551CON1**

### U.S. PATENT DOCUMENTS

Examiner Initials*	Cited No. <sup>1</sup>	Document Number Number - Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear
<i>JK</i>	A01	US-5,910,897	06/1999	Dangelo	
<i>NW</i>	A02	US-6,295,623	B1	Lesmeister	

### FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Cntry Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear	T <sup>6</sup>

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>NW</i>	Martinolle, F. et al. "A procedural language interface for VHDL and its typical applications," Jan. 1998, ACM, pp. 32-38
	Gough, G. et al. "A design and verification environment for ELLA," Sep. 1995, IEEE, pp. 685-690
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<i>Y</i>	York, G. "An integrated environment for HDL verification," Mar. 1995, IEEE, pp. 9-18

EXAMINER SIGNATURE: *[Signature]*DATE CONSIDERED: *12/8/05*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.

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